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TRANSMIPTAL FORM			Application No.	10/5	1,571	
			Filing Date	May	16, 2005	
(to be used for all	correspondence aft	er initial filing)	First Named Inventor	Paul	Frederick Fewster	
			Art Unit	2882		
			Examiner Name	Yun,	Jurie	
Total Number of Pa	ges in This Submission	11	Attorney Docket Numbe	r 5926	P037	
	ENCLO	SURES (chec	k all that apply)			
Fee Transmittal		Drawing(s)			After Allowance Communication to TC	
Fee Attach	ned	Licensing-re	elated Papers		Appeal Communication to Board of Appeals and Interferences	
Amendment / Re	ply	Petition			Appeal Communication to TC (Appeal Notice, Brief, Reply Brief)	
After Final	declaration(s)	Petition to C Provisional	Convert a Application		Proprietary Information	
Extension of Time	e Request	Power of Al Change of 0	torney, Revocation Correspondence Address		Status Letter	
Express Abandonment Request Information Disclosure Statement		Terminal Disclaimer Request for Refund			Other Enclosure(s) (please identify below): European Patent Office Communication; Japanese	
_	PTO/SB/08 Certified Copy of Priority Document(s)		CD, Number of CD(s) Landscape Table on CD		Office Action with English ranslation; 8 prior art efferences; postcard	
Document(s) Response to Missing Parts/ Incomplete Application					Sicronecs, posteard	
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	SIGNATURI	E OF APPLICAN	IT, ATTORNEY, OR A	GENT		
Firm or	Eric S. Hyman	, Reg. No. 30,	139	<u>-</u>		
Individual name	BLAKELY, S	OKOLOFF,	TAYLOR & ZAF	MAN	LLP	
Signature			\sim			
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hereby certify that this postage as first class ma	соггеspondence is being ail in an envelope addre	g deposited with the ssed to: Commissi	e United States Postal Second for Patents, P.O. Box	vice on th 1450, Ale	e date shown below with sufficient xandria, VA 22313-1450.	
Typed or printed na	me Vi Hoang					
Signature		1		Date	1/23/67	

JAN 2 9 . 2007					
FEE TRANSMIT	TAI	Complete if Known			
		Application Number	10/511,571		
for FY 2006		Filing Date	October 12, 2004		
Patent fees are subject to annual revision		First Named Inventor	Paul Frederick Fewster		
Applicant claims small entity status. See 33	7 CFR 1.27.	Examiner Name			
		Art Unit			
TOTAL AMOUNT OF PAYMENT (5)	Attorney Docket No.	5926p037		

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METHOD OF PAYMENT (check all that apply)										
☐ Check ☐ Cre	dit ca	ırd 🔲 M	oney Or	der None	Other (please identify):					
Deposit Account Deposit Account Number: 02-2666 Deposit Account Name: Blakely, Sokoloff, Taylor & Zafman LLP										
For the above	-iden	ntified dep	osit acc	ount, the Director is h	nereby authorized to: (check	all that apply)				
	Charge fee(s) indicated below Charge fee(s) indicated below, except for the filing fee									
Charge any additional fee(s) or underpayment of fee(s) Credit any overpayments under 37 CFR §§ 1.16, 1.17, 1.18 and 1.20.										
FEE CALCULATION										
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Large Entity		Small								
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	90	2810	395	For each addition	al invention to be exam	ined (37 CFR § 1.129(b))			
Other fee (spe	cify)								
						SUBTOTAL (2)	5)			
SUBMITTED BY Complete (if applicable)										

Docket No.: 5926P037

N THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of:

PAUL FREDERICK FEWSTER

Application No.: 10/511,571

Filed: October 12, 2004

For: X-Ray Diffraction Apparatus and Method

Art Group:

Examiner:

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

In accordance with the duty of disclosure, enclosed is a copy of IDS Citation Form PTO/SB/08 or PTO-1449, together with copies of the documents cited on that form, except for copies not required to be submitted (e.g., copies of U.S. patents and U.S. published patent applications need not be enclosed). This IDS and IDS Citation Form are being submitted before the mailing of a final Office Action. It is respectfully requested that the cited references be considered and that the enclosed copy of PTO/SB/08 be initialed by the Examiner to indicate such consideration and a copy thereof returned to applicant(s).

It is hereby stated that no item of information contained in the Information Disclosure Statement was cited in a patent office in a counterpart application, and, to the knowledge of the undersigned, after making reasonable inquiry, no item of information contained in the Information Disclosure Statement was known to any individual associated with the filing or prosecution of the subject application more than three months prior to the filing of the Information Disclosure Statement.

-1- 5926P037

The references were cited in Search Reports dated October 24, 2006 and November 24, 2006 which were forwarded to Applicant's Representative in a communication dated October 24, 2006 and November 24, 2006 (copies enclosed).

The submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made in the subject application and is not to be construed as an admission that the information cited in this statement is material patentability.

Please charge any additional fee due to Deposit Account 02-2666. A duplicate copy of the Fee Transmittal (PTO/SB/17) is enclosed for this purpose.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Eric Hyman

Reg. No. 30,139

CERTIFICATE OF MAILING

12400 Wilshire Boulevard, Seventh Floor Los Angeles, California 90025 (310) 207-3800 I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on: 123/07

Vi Hoang

Date

Substitute for form 1449A/PTO

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

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of

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	Complete if Known
Application Number	10/511,571
Filing Date	October 12, 2004
First Named Inventor	Paul Frederick Fewster
Art Unit	
Examiner Name	
Attorney Docket Number	5926P037

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5	U.S. PATENT DOCUMENTS									
Exminer Mitials	Cite No.1	Document Number Number - Kind Code² (if known)	Publication Date or Issue Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear					
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Examiner	Cite	Foreign Patent Document			Pages Columns Lines	
Initials*	No.1	Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		JP 2001-141674	05-25-2001	Canon Inc.		Ab.
		JP 03-156350	07-04-1991	Nippon Telegr & Teleph		Ab
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^{*}Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

Substitute	for form 1449A/PTO			Complete if Known		
INITO	RMATION DIS	· C I .	SCUDE	Application Number	10/511,571	
INFO	KINIA HON DIS	CL	JOUKE	Filing Date	October 12, 2004	
STAT	EMENT BY A	PPL	ICANT	First Named Inventor	Paul Frederick Fewster	
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Sheet	2	of	2	Attorney Docket Number	5926P037	

	NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No.¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²			
		"Grazing excidence diffraction versus grazing incidence diffraction for strain/stress evaluation in thin films" by ANOUAR NJEH et al.; <i>Powder Diffraction 15</i> (4), December 2000; pp 211-216				
		"Submicron x-ray diffraction and its applications to problems in materials and environmental science" by N. TAMURA et al.; <i>Review of Scientific Instruments</i> ; Volume 73, Number 3, March 2002; pp. 1369-1372				
		"Submicron X-ray diffraction" by A.A. MacDowell et al.; Nuclear Instruments and Methods in Physics Research A 467-468 (2001); pp. 936-943				
		"Crystallographic Analysis of CVD Films by Using X-Ray Polychromatic Radiation" by B. Lavelle, et al.; 1998 Materials Research Society Symp. Proc. Vol. 524; pp. 121-126				
		"Image Plates as One-Dimensional Detectors in High-Resolution X-ray Diffraction" by A. KINNE et al.; <i>J. Appl. Cryst.</i> (1998); pp. 446-452				
		"Real-time in situ x-ray diffractioin as a method to control epitaxial growth" by A.S. BADER et al.; Applied Physics Letters, Volume 82 Number 26; June 30, 2003; pp. 4684-4686				

Examiner	Date	
Signature	Considered	

Based on PTO/SB/08B (08-03) as modified by Blakely, Solokoff, Taylor & Zafman (wtr) 08/11/2003. Send To: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450

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